Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/657,754	KIM, HEE JEAN
Examiner	Art Unit
Tongoc Tran	2134

	SEAR	CHED	
Class	Subclass	Date	Examiner
380	201-202	4/26/2007	T [*] T
380	211,241	4/26/2007	TT
380	278	4/26/2007	π

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEAR)	IOTES CH STRATEGY)
	DATE	EXMR
East	4/26/2007	тт
Inventor name search	4/26/2007	тт
ACM, IEEE	4/26/2007	т
East	4/27/2007	тт
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